

DATA SHEET

NE57814

DDR memory termination regulator with
standby mode and enhanced efficiency

Product data
Supersedes data of 2003 Jan 22

2003 Apr 03

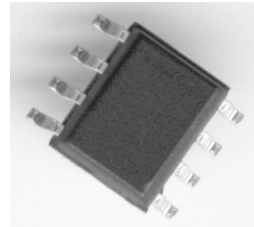
DDR memory termination regulator with standby mode and enhanced efficiency

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DESCRIPTION

The NE57814 is designed to provide power for termination of a DDR memory bus. It significantly reduces parts count, board space, and overall system cost over previous switching solutions. The NE57814 has an independent power source pin (V_D) for further reducing the operational power and a standby low-power mode for energy-sensitive portable applications.

The DDR terminator regulator provides a very accurate reference (RefOut) and termination voltage (V_{TT}) which is one-half of the RAM supply voltage over wide range of current demand.



HSO8 (TOP)



HSO8 (BOTTOM)

FEATURES

- Fast transient response time
- Over-temperature protection
- Over-current protection
- Commercial (0 °C to 70 °C) temperature range
- High bandwidth drivers minimize requirement for output hold-up filter capacitors
- Internal divider maintains termination voltage at $1/2$ memory supply voltage
- RefOut output pin for other memory and control components

APPLICATIONS

- Laptop computers
- Desktop microcomputer systems
- Workstations
- Set-top boxes
- Servers
- Networking routers and switches
- Video display systems
- Personal video recorders
- Game machines
- Embedded systems

SIMPLIFIED SYSTEM DIAGRAM

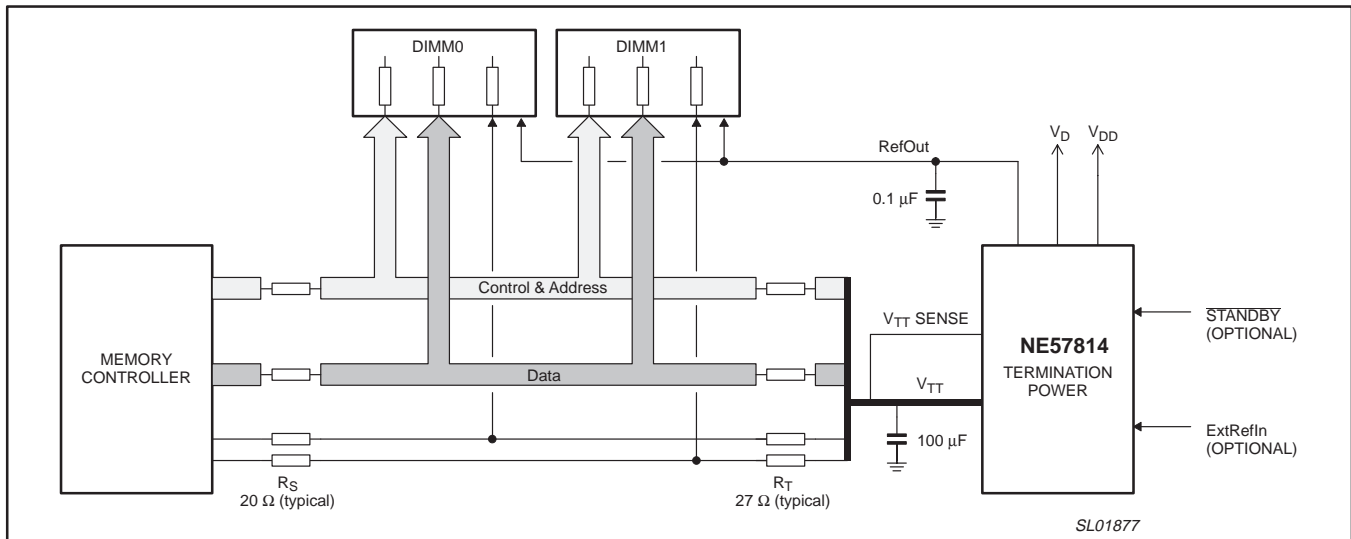


Figure 1. Simplified system diagram.

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ORDERING INFORMATION

TYPE NUMBER	PACKAGE			TEMPERATURE RANGE
	NAME	DESCRIPTION	VERSION	
NE57814DD	HSO8	plastic thermal enhanced small outline package; 8 leads; body width 3.9 mm; exposed die pad	SOT786-2	0 °C to +70 °C

PIN CONFIGURATION

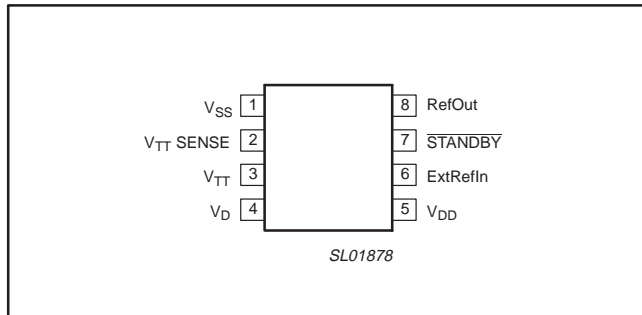


Figure 2. Pin configuration.

PIN DESCRIPTION

PIN	SYMBOL	DESCRIPTION
1	V_{SS}	Terminator ground
2	V_{TT} SENSE	V_{TT} remote sense. Connect to pin 3 (V_{TT})
3	V_{TT}	Terminator voltage output
4	V_D	V_{TT} output MOSFET drain
5	V_{DD}	DDRAM supply voltage
6	ExtRefIn	Reference node used for external control of V_{TT}
7	STANDBY	Places device into standby mode (active-LOW)
8	RefOut	Buffered V_{TT} reference output, used for cascading terminators

NOTE:

- The thermal heatspreader connects electrically to V_{SS} internally and provides enhancement to thermal conductivity, but it should not be used as the primary connection to ground. Device specifications apply to use of the V_{SS} pin as the connection to ground.

MAXIMUM RATINGS

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNIT
V_{DD}	V_{DD} to V_{SS} voltage	-0.3	-	+3.6	V
T_{amb}	Operating ambient temperature	0	-	+70	°C
T_{stg}	Storage temperature	-40	-	+165	°C
T_j	Junction temperature	-	-	160	°C
$R_{th(j-a)}$	Thermal resistance, junction to ambient (Note 1)	-	38.5	-	°C/W
P	Power dissipation (Note 1)	-	-	2.1	W

NOTE:

- Tested on a minimum footprint on a four-layer PCB per JEDEC specification JESD51-7.

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ELECTRICAL CHARACTERISTICS

$T_{amb} = 0\text{ }^{\circ}\text{C}$ to $+70\text{ }^{\circ}\text{C}$; $V_{DD} = 2.5\text{ V}$; $V_D = 2.5\text{ V}$, unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
V_{TT}	Output voltage	ExtRefIn not connected	–	$V_{DD}/2$	–	V
	Output voltage accuracy error	$V_{TT} - V_{DD}/2$; $I_{TT} = 0\text{ A}$	–15	–	+15	mV
V_{DD}	Supply voltage		1.6	–	3.6	V
V_D	Supply voltage on pin V_D		1.6	–	3.6	V
$I_{Q(OP)}$	Operating supply current	$I_{TT} = 0\text{ A}$	–	14	30	mA
I_{TT}	Output current (Note 5)	$V_D = V_{DD} = 2.5\text{ V}$ to 3.6 V	–3.5	–	+3.5	A
		$V_D = V_{DD} = 1.6\text{ V}$	–2.5	–	+2.5	A
$I_{Q(SD)}$	Standby quiescent current	Standby asserted	–	1.2	1.35	mA
ΔV_{TT}	Load regulation	$I_{TT} = \pm 1.0\text{ A}$	–	± 6	–	mV
		$I_{TT} = \pm 3.5\text{ A}$	–18	–	+18	mV
C_{LOAD}	Min. load capacitance (Note 2)	Stable operation	50	100	–	μF
External Reference In						
$V_{ExtRefIn}$	ExtRefIn voltage range		0.8	–	$V_{DD} - 0.8$	V
R_{in}	ExtRefIn input impedance		35	50	–	k Ω
$V_{ExtRefIn} - V_{TT}$	Output voltage accuracy	$I_{TT} = 0\text{ A}$	–15	–	+15	mV
	Line regulation	$V_{ExtRefIn} = 1.25\text{ V}$; $V_{DD} = 2.25\text{ V}$ to 3.6 V	–6	–	+6	mV
Reference Out						
V_{ERRREF}	Voltage reference out (Note 4) accuracy error, $V_{ExtRefIn} - V_{RefOut}$	$I_{RefOut} = 0\text{ A}$	–15	–	+15	mV
I_{RefOut}	Reference Out current limit	source or sink	2.2	3	–	mA
C_{LOAD}	Load capacitance	Stable operation	0.1	–	–	μF
Power Stage						
I_{lim}	Current limit		3.6	4.5	6.5	A
$R_{ds(on)}$	Source transistor on-resistance		–	0.18	0.32	Ω
T_{lim}	Temperature shutdown		–	+150	–	$^{\circ}\text{C}$
	Temperature shutdown hysteresis		–	20	–	$^{\circ}\text{C}$

NOTE:

- Limits are 100% production tested at $25\text{ }^{\circ}\text{C}$. Limits over the operating temperature range are guaranteed through correlation using Statistical Quality Control (SQC) methods.
- Ceramic capacitors. Low ESR Electrolytic capacitors are not required for stability, but may be needed for the application.
- Voltage Accuracy referred to voltage at the center node of the V_{ref} resistor divider.
- RefOut voltage referenced to $1/2 V_{DD}$.
- See Figure 15 for the Safe Operating Area versus Temperature.

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TYPICAL PERFORMANCE CURVES

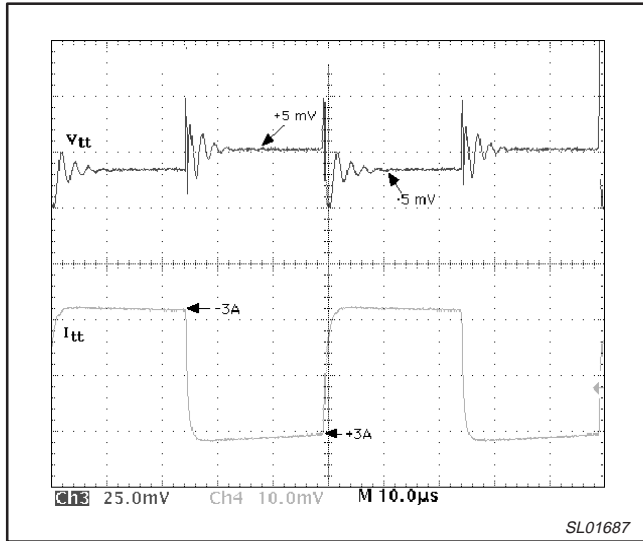


Figure 3. V_{TT} transient response (output filter 50 μ F ceramic)

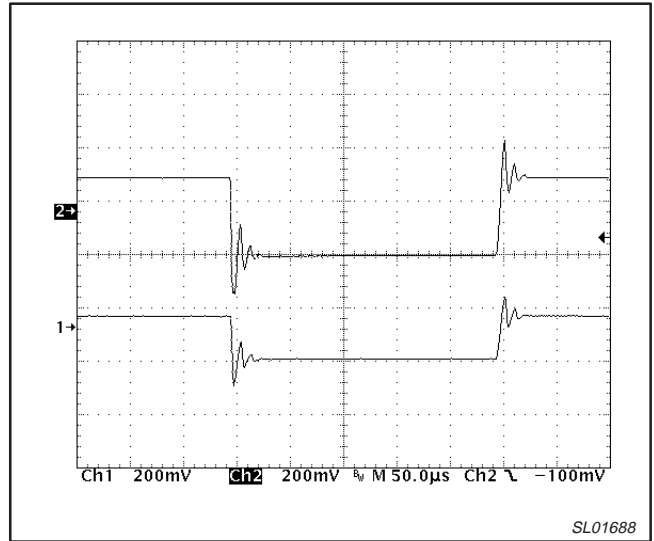


Figure 4. V_{DD} -to- V_{TT} response (output filter 50 μ F ceramic)

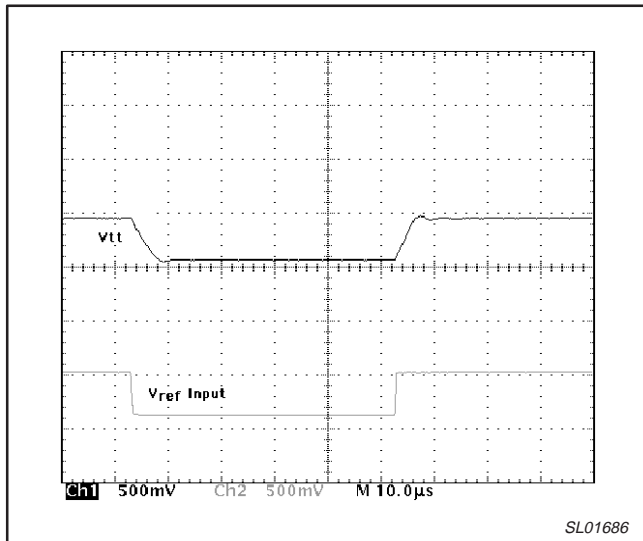


Figure 5. V_{ref} -to- V_{TT} transient response (output filter 820 μ F + 50 μ F ceramic)

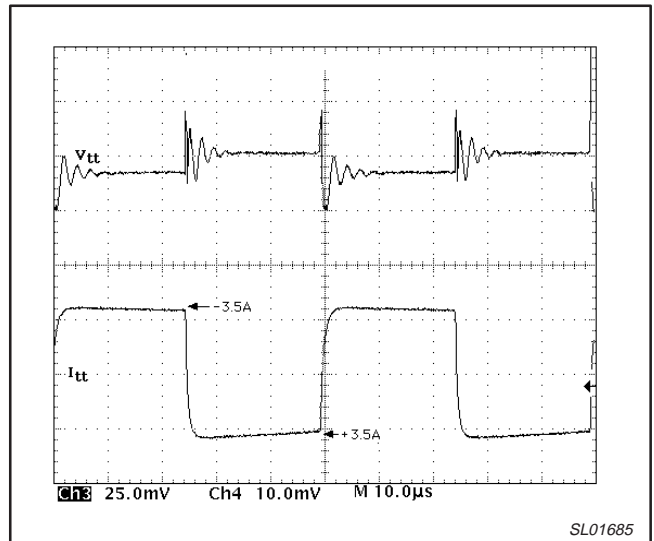


Figure 6. V_{ref} -to- V_{TT} transient response (output filter 50 μ F ceramic)

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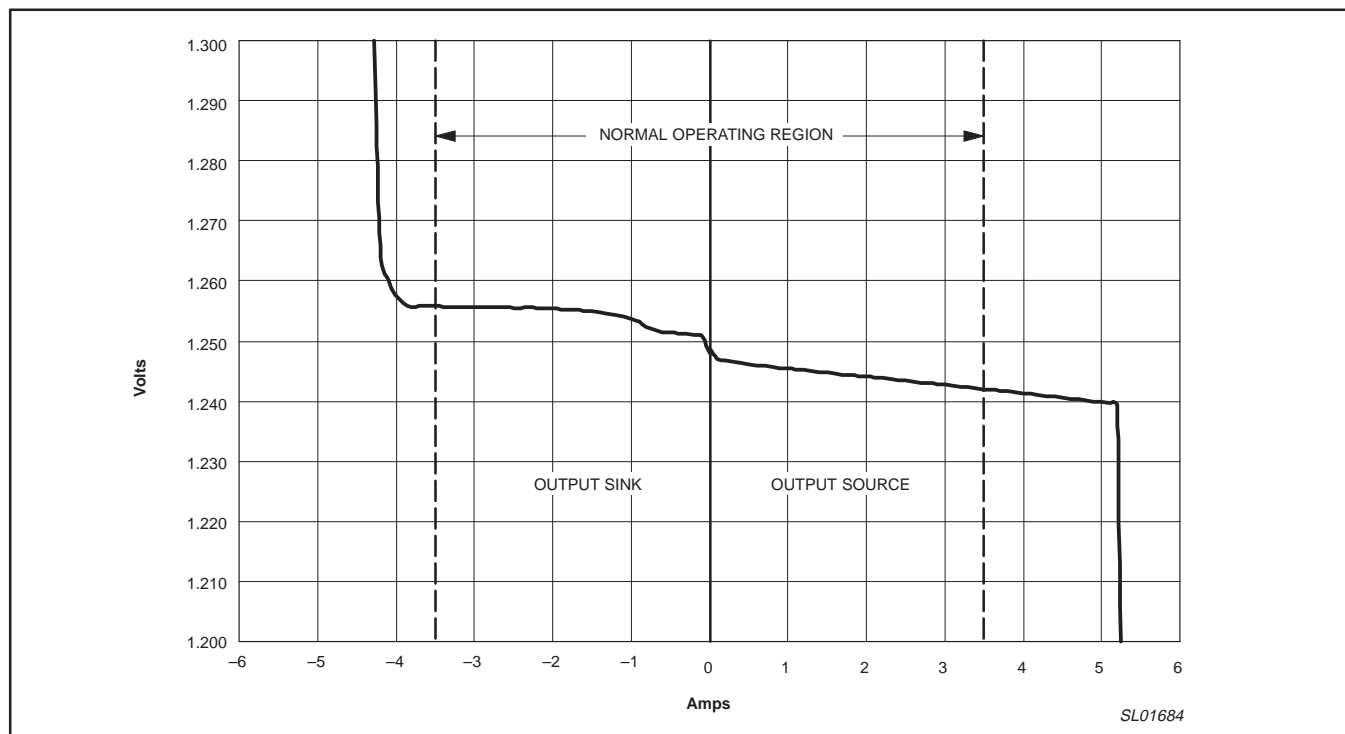


Figure 7. Output regulation.

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TECHNICAL DISCUSSION

The NE57814 supplies power to the DDR memory bus termination resistors at one-half the voltage supplied to the memory ICs or DIMMs. The DDR memory bus can only have one output drive any one bus line at any one time. So the load on the DDR termination system is a matter of the number of bus lines being terminated and the termination resistor values. The memory size (that is the MB) of memory space is not relevant. A typical DDR memory system is seen in Figure 8. Each bus input/output pin on the bus has a series 20 Ω resistor connected to it. The bus is terminated to the DDR terminator through a 27 to 50 Ω resistance. The memory system will then require current from the terminator output only when the instantaneous value of the aggregate bus does not correspond to equal amounts of 1s and 0s. When memory bus speeds are in the 200–300 MHz region, the period of any single bus state is extremely small. This creates two bus loading conditions: the high frequency condition which is caused by the instantaneous numbers of 1s and 0s, and the low frequency condition caused by mainly the address bus being oriented towards the top or bottom of the memory space. This creates two relatively independent output-filtering situations for the DDR terminator: the high frequency bus speed, and the low-frequency address skew of the processor system. Each should be examined separately.

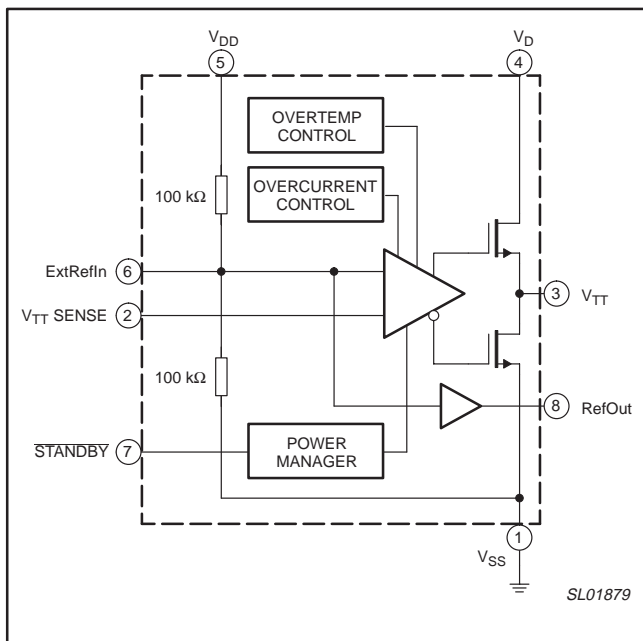


Figure 8. Functional diagram.

Figure 9 models the V_{TT} loading condition of each bus line equivalent circuit during operation and with terminating resistors.

This yields the worst case current loading equation:

$$I_{O(max)} = \frac{N_{DDR} V_{DD}}{2(R_T + R_S)}$$

Where:

N_{DDR} is the total number of terminated control, address and data lines within the DDR memory system (typically 192).

R_T is the value of the terminating resistors.

R_S is the value of the series resistors from the active output driver.

Hence the worst-case current loading condition for the typical DDR memory is 194 terminated bus lines, and there are either all 1s or all 0s for an instant. If the terminator resistances are $R_T = 27 \Omega$ and $R_S = 20 \Omega$, then this results in a momentary instantaneous output current of either + or – 3.3 Amperes.

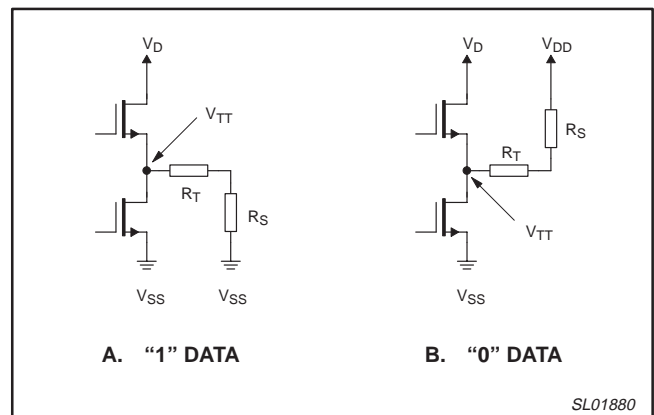


Figure 9. The model for a single bus line for the DDR system.

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APPLICATION INFORMATION

The NE57814 is intended for DDR memory termination systems which require small space, low cost, high output transient current dynamic range, and higher efficiency than the traditional linear DDR terminator. The increased efficiency is gained by being able to draw its output current from a lower voltage than the DDR RAM V_{DD} voltage. As much as a 40 percent in the overall efficiency can be gained by operating the output stage from a voltage source of 0.25 V above the output V_{TT} voltage. This gives it a distinct benefit in portable applications.

The standby mode turns OFF the V_{TT} amplifier and 3-states the V_{TT} output. The RefOut pin is still active for use elsewhere within the system.

Using the $\overline{\text{STANDBY}}$ signal

The NE57814 provides a $\overline{\text{STANDBY}}$ pin that can be used to put the device into low-power mode. When $\overline{\text{STANDBY}}$ is asserted (LOW), the V_{TT} power amplifier is turned off and the V_{TT} output is 3-stated. This brings the quiescent current of the entire device to less than 800 μA . The internal reference divider (ExtRefIn pin) and the reference amplifier will remain active, allowing those circuits requiring a reference during the $\overline{\text{STANDBY}}$ state to remain active.

If $\overline{\text{STANDBY}}$ is not externally connected, an internal 10 k Ω resistor biases the control logic to V_{DD} causing the output sections to be turned on and the NE57814 operates normally.

Output filtering

There are two components to the memory signal load: a high frequency component caused by the 266 MHz plus speed of the address, data, and control buses, and a low frequency component caused by the time-average skew of all of the bus states away from

an equal number of 1s and 0s. All electrolytic and tantalum capacitors appear inductive at the high frequencies. Therefore two types of capacitors are needed for the output filtering.

For a 256 MB memory space, for example, approximately 100 μF of ceramic surface mount ceramic capacitors should be evenly distributed across the physical memory layout. Depending upon the PCB noise environment, this could be 10 pieces of 10 μF , 20 pieces of 5 μF , and so on. These are the high frequency filter, represented by C_{out} (HF) in the illustrations. One half of the high frequency filter capacitors should be connected to V_{DD} and the other half to V_{SS} so that the output will better track any variations in the V_{DD} voltage.

Filtering the lower frequencies of the DDR load usually requires larger, low-ESR capacitors such as tantalum or low-ESR electrolytic capacitors, shown as C_{out} (LF) in the illustrations.

This is where the NE57814 excels. Because of its fast input and output transient responses, very small or no additional large capacitors are needed. Worst-case system analysis has shown that an additional 110 μF of capacitance is needed for each microsecond lag in the response time of the DDR regulator. The NE57814 responds in within one microsecond, so this requirement can be filled by the 100 μF of ceramic capacitors already on the output.

Additional studies have shown that other regulators, which cannot directly source the maximum instantaneous current demanded from the termination system, must have an additional 75 μF of capacitance for each ampere of insufficient output drive.

Together, the fast output response and peak drive current capabilities make the NE57814 the ideal choice for DDR termination.

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High efficiency operating mode

The NE57814 is designed for portable applications such as laptop computers and other battery operated computer systems requiring DDR memory. The standby mode 3-states the V_{TT} output and unpowers most of the NE57814, which is very desirable for portable applications. The RefOut pin is still active for use elsewhere within the system.

The V_D pin on the NE57814 allows the DDR termination system to operate with reduced output power dissipation. The V_D voltage can be lowered to approximately +0.25 volts above the V_{TT} output voltage.

The high-efficiency method draws its V_{TT} current, not from the memory V_{DD} line but from a lower voltage, V_D . This will decrease the loss within the terminator when it sources current to the V_{TT} line. The V_D voltage required depends on the load current sourced and is given by $V_{D(min)} = V_{TT} + 0.3(I_{TT(source)})$. I_{TT} is expressed in amps.

The V_{DD} voltage is still used to set the V_{ref} voltage to the memory devices.

As much as a 65 percent overall efficiency can be gained by operating the output stage from a voltage source of 0.25 V above the output V_{TT} voltage during the sourcing condition. This gives it a distinct benefit in portable applications.

The efficiency of the DDR terminator during the sourcing and sinking states of the NE57814 can be determined by the following calculations:

Sourcing:

$$Efficiency(sourcing) = \frac{[(V_{TT}) (I_{TT})]}{[(I_Q) (V_{DD}) + (V_D - V_{TT}) (I_{TT})]} \times 100$$

This can be between 81 and 82.5 percent when the NE57814 is sourcing current.

Sinking:

$$Efficiency(sinking) = \frac{[(V_{TT}) (I_{TT})]}{[(I_Q) (V_{DD}) + (V_{TT}) (I_{TT})]} \times 100$$

This is approximately 49.5 percent.

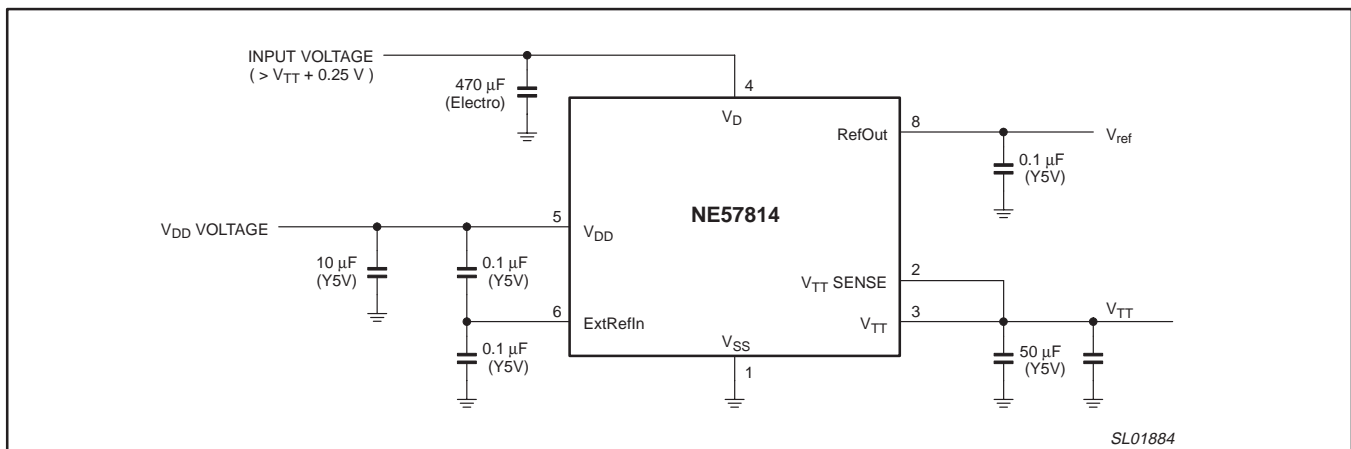


Figure 10. High efficiency operation.

Less than +0.25 V between V_D and V_{TT}

A voltage difference between V_D and V_{TT} of less than +0.25 V reduces the maximum sourcing current capability of the V_{TT} power amplifier.

This reduction in output sourcing current capability can many times be compensated for within the termination system by adding additional low ESR electrolytic capacitors on the V_{TT} output. The typical performance of the NE57814 as the V_D voltage approaches V_{TT} voltage (decreasing headroom voltage) can be seen in Figure 11.

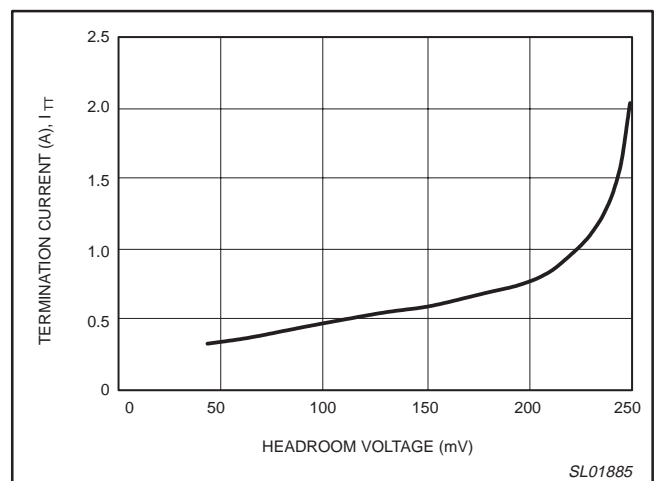


Figure 11. Typical output source current versus V_D (at 25 °C).

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Single-supply operating mode (V_{DD} supply only)

For single-supply operation, connect the V_D pin to the V_{DD} pin. This is suitable for use in a desktop computer or other non efficiency-sensitive application (see Figure 12).

Externally setting V_{TT}

The NE57814 allows use of an external reference voltage applied to the ExtRefIn pin to set the V_{TT} output voltage. This pin is used for applications where the V_{TT} voltage is not equal to V_{DD} divided by 2. The needed V_{TT} voltage and current may be drawn from a power supply bus that is not the DDR RAM supply voltage. This may have some advantages when the system designer is attempting to better match the power being drawn from the outputs emerging from main system power supply.

The internal reference voltage is set by two matched 100 k Ω resistors connected in a resistor divider between the V_{DD} and V_{SS} pins of the NE57814. Setting the value of V_{ref} or V_{TT} can be done in two ways: by using an external resistor divider whose resistor values are less than 5 k Ω each or by connecting the output of an operational amplifier which is outputting the reference voltage to the ExtRefIn pin.

If the external resistor divider is used, place a 0.01 μ F ceramic bypass capacitor between the ExtRefIn pin (pin 6) and the V_{SS} pin (pin 1). The accuracy of the new reference voltage when the external resistor divider is used will be about 0.5 percent PLUS the sum of the tolerances of the resistors used in the divider.

Please note that when the NE57814 is operating in this fashion, the power dissipation of the part may increase.

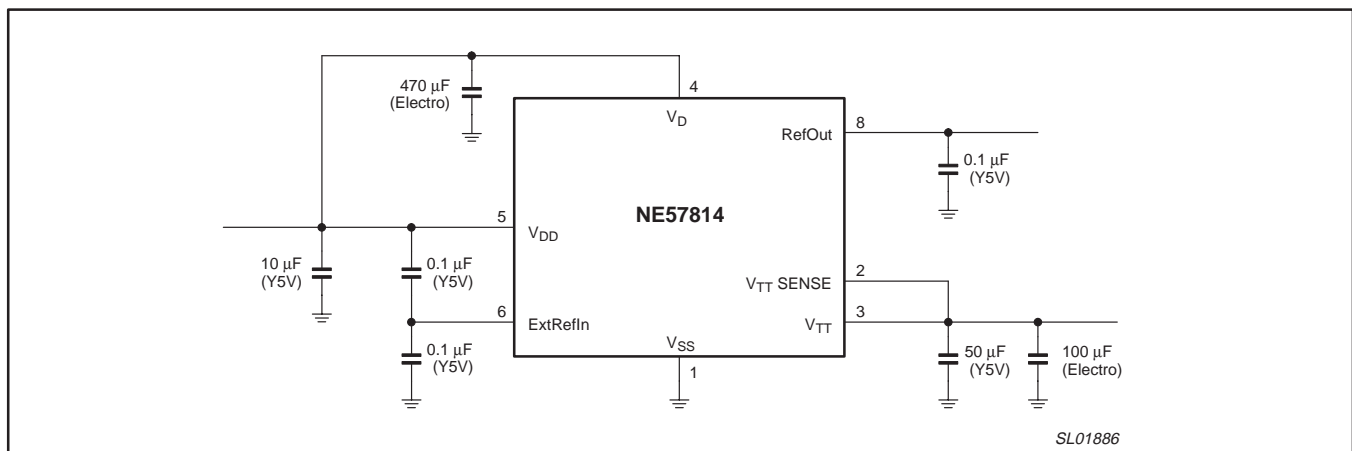


Figure 12. Single-supply operation.

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Cascading the NE57814 for complex memory systems

For high-performance computer systems, such as workstations and servers, where two or more banks of independent memory arrays are needed, the NE57814 can be cascaded to provide two independent, but slaved termination systems. This type of architecture allows the termination voltages to be within 12 mV of one another, and the V_{TT} can be controlled from a single node.

Cascading NE57814 terminators offers two advantages; memory SIMMs can be brought closer to the terminator, which improves the

system noise, and it will better distribute any heat generated by the terminator system. Use the RefOut pin from one NE57814 to the ExtRefIn pin for the other NE57814(s) in the system to ensure that the V_{TT} voltages are identical.

The output of the NE57814 is a very low impedance voltage source which means that the V_{TT} outputs should never be wired together. That is, NE57814s should never be wired in parallel. This is because the terminators would “fight” one another if their output were different by only a few millivolts.

The cascading method can be seen in Figure 13.

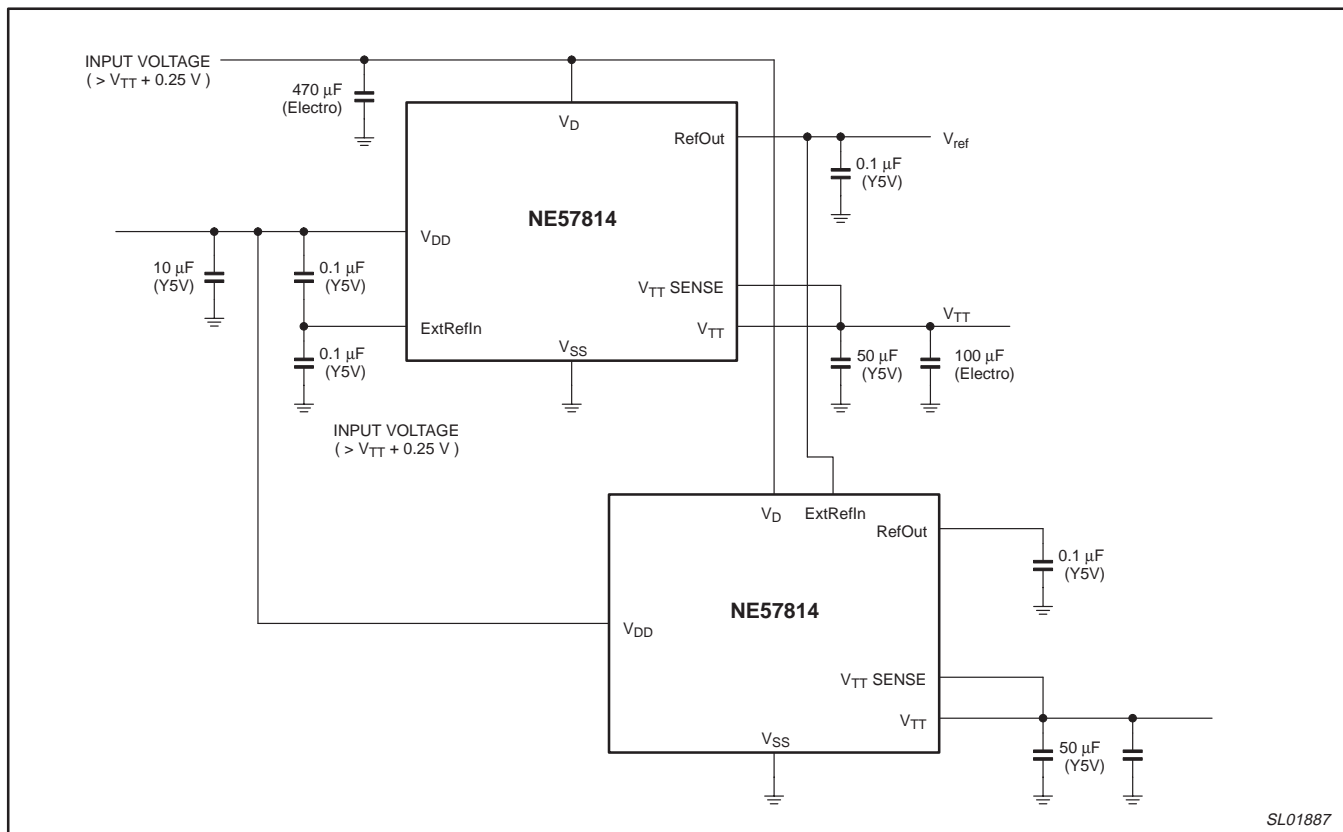


Figure 13. Cascading terminator systems for complex memory systems.

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THERMAL DESIGN

Designing the thermal system for the NE57814 is important for its reliable operation. The NE57814 will be operating at an average power level less than the maximum rating of the part. In a typical DDR terminator system the average power dissipation is between 0.8 and 1.5 watts. It is important to make sure that this average power dissipation is less than the power capability of the package.

The terminator heatsink must be designed to accommodate the average power as a steady state condition and be able to withstand momentary periods of increased dissipation, say from 1–2 seconds. For the single-supply application, the power dissipated by the terminator can be calculated:

$$P_D = I_{DD} \times V_{TT} \text{ Watts} \tag{Eqn. (1)}$$

The thermal resistance of a surface mount package is given as $R_{th(j-a)}$ (thermal resistance from the junction to air). JESD51-7 specifies a 4-layer PCB (2oz/1oz/1oz/2oz copper) that is 4 inches on each side. This is probably the best (or lowest thermal resistance) one will see in any application. Most applications cannot afford the PCB area to create this situation, but the thermal performance of a multi-layer PCB will still provide a significant heat sinking effect. The actual thermal resistance will be higher than the 38.5 °C/W given for the 4-layer JEDEC PCB.

Figure 14 shows what thermal resistance one can expect for heat sinking PCB areas less than the JEDEC specification. The resistance can be decreased by using a double-sided PCB with some plated through holes (vias) to help transfer the heat to the bottom side. The thermal resistance decreases by about 3–4 °C/W for a double-sided board with vias.

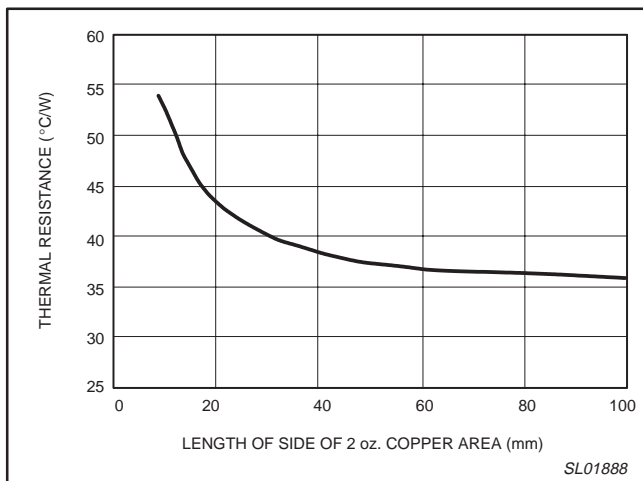


Figure 14. Thermal resistance versus PCB area.

After the power is estimated, the minimum PCB area can be determined by calculating the worst-case thermal resistance and referring to Figure 8 to determine the PCB area. This is done by:

$$R_{th(j-a)(min)} = \frac{T_j - T_{amb}}{P} \tag{Eqn. (2)}$$

Where:

- T_j is the maximum desired junction temperature.
- T_{amb} is the highest expected local ambient temperature.
- P is the estimated average power

The junction temperature should be kept below the over-temperature cutoff threshold temperature (+140 °C) in normal operation.

Using the power dissipation formula above, the highest ambient temperature, 1.5 watts power dissipation (used only as an example) and a junction temperature of +125 °C, calculate the maximum thermal resistance as follows:

$$R_{th(j-a)(min)} = \frac{140\text{ }^{\circ}\text{C} - 70\text{ }^{\circ}\text{C}}{1.5\text{ W}} = 47\text{ }^{\circ}\text{C/W} \tag{Eqn. (3)}$$

Looking at Figure 15, a minimum PCB island area of 225 mm² (15 mm length and width) is required at this power dissipation. Of course, increasing this area will allow the NE57814 to operate at cooler temperatures, enhancing the long-term reliability and allowing the terminator to better handle any transient output current demands.

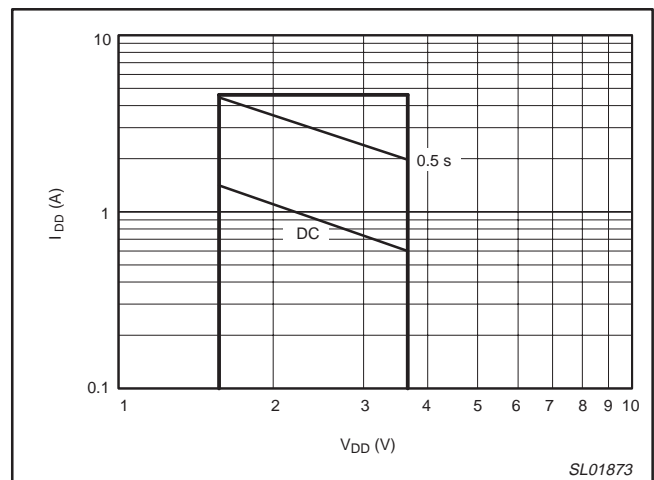


Figure 15. Safe operating area of the NE57814.

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PACKING METHOD

The NE57814 is packed in reels, as shown in Figure 16.

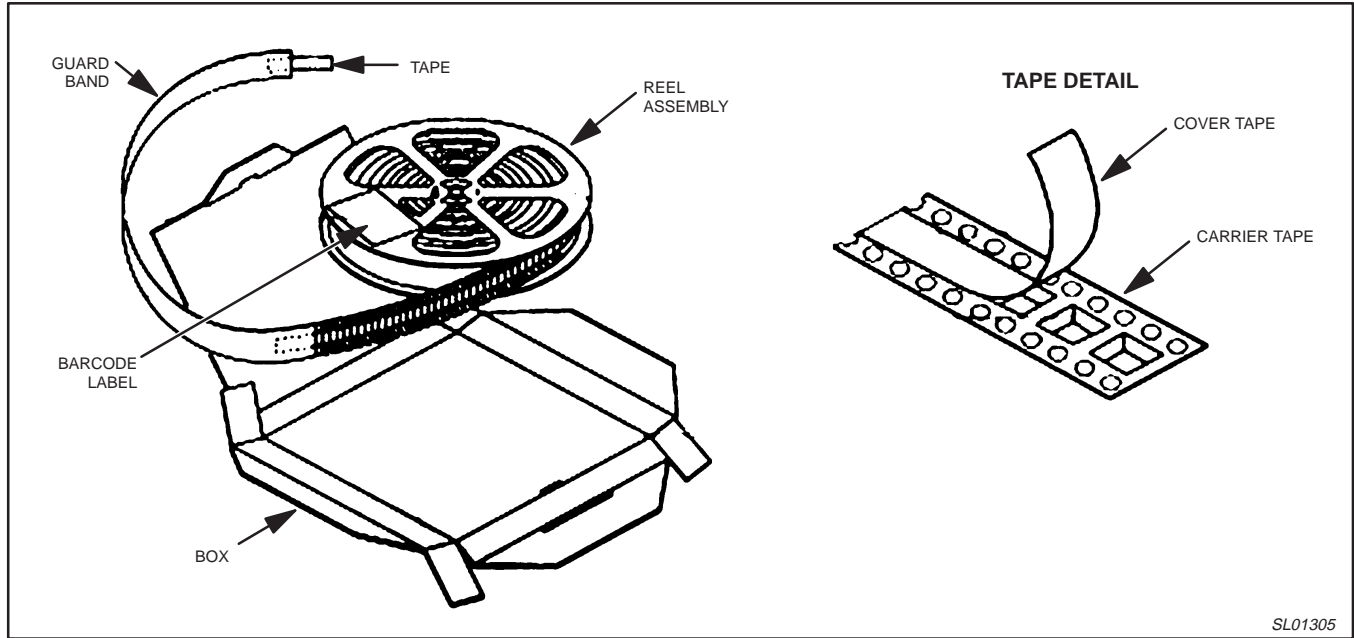


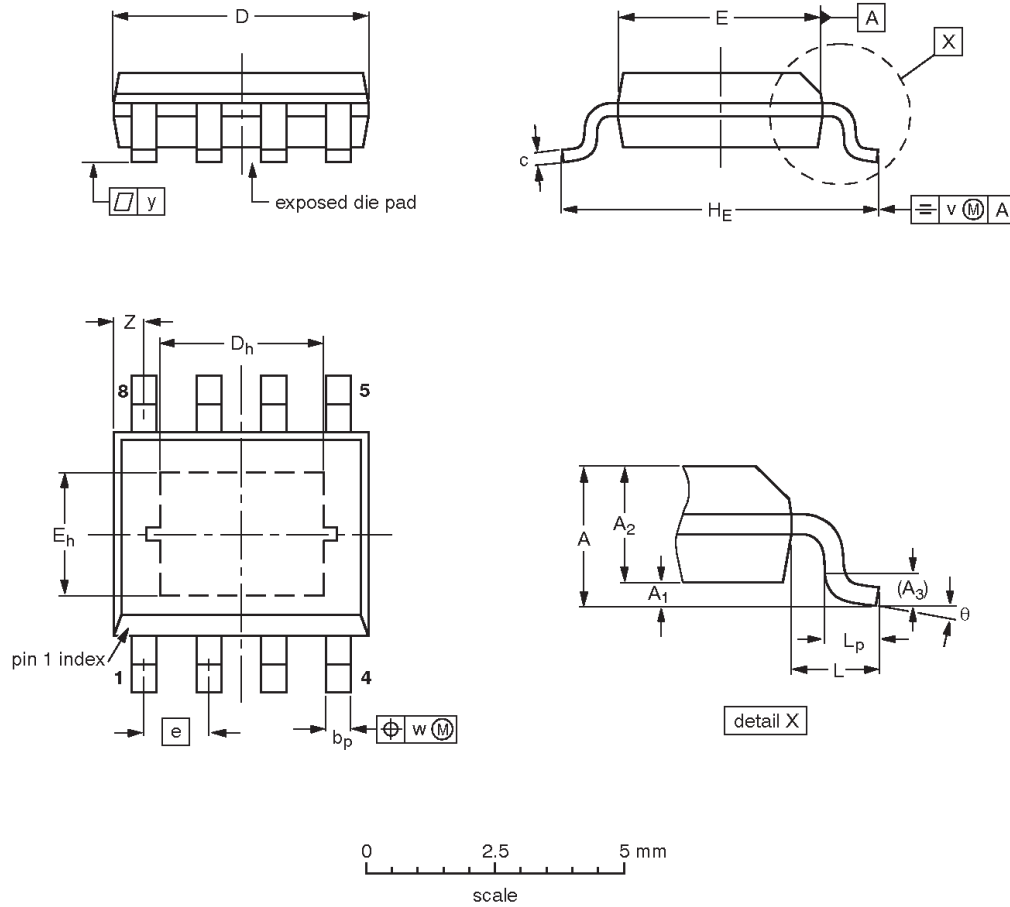
Figure 16. Tape and reel packing method.

DDR memory termination regulator with standby mode and enhanced efficiency

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HS08: plastic thermal enhanced small outline package;
8 leads; body width 3.9 mm; exposed die pad

SOT786-2



DIMENSIONS (mm dimensions are derived from the original inch dimensions)

UNIT	A max.	A ₁	A ₂	A ₃	b _p	c	D ⁽¹⁾	D _h	E ⁽²⁾	E _h	e	H _E	L	L _p	v	w	y	Z ⁽¹⁾	θ
mm	1.7	0.1 0.0	1.6 1.4	0.25	0.49 0.36	0.25 0.19	5.0 4.8	3.17 2.97	4.0 3.8	2.49 2.29	1.27	6.2 5.8	1.05	1.0 0.4	0.25	0.25	0.1	0.8 0.3	8° 0°

Notes

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
2. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA			
SOT786-2						02-10-02

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REVISION HISTORY

Rev	Date	Description
3	20030403	<p>Product data (9397 750 11217); ECN 853-2399 29610 of 03 March 2003; supersedes data of 2003 Jan 22 (9397 750 10984).</p> <p>Modifications:</p> <ul style="list-style-type: none"> ● Description on page 2, second paragraph: delete second sentence. ● Electrical Characteristics table on page 4: <ul style="list-style-type: none"> – Symbol $I{Q(OP)}$: change Typ. value from 20 mA to 14 mA. – Symbol $I_{Q(SD)}$: change Typ. value from (–) to 1.2 mA. – Add new Note 1, and renumber following notes and their references.
_2	20030122	<p>Product data (9397 750 10984); ECN 853-2399 29323 dated 2002 Dec 19; supersedes Objective data of 2002 Nov 07 (9397 750 10618).</p>
_1	20021107	<p>Objective data; initial version (9397 750 10618).</p>

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Data sheet status

Level	Data sheet status ^[1]	Product status ^{[2] [3]}	Definitions
I	Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
II	Preliminary data	Qualification	This data sheet contains data from the preliminary specification. Supplementary data will be published at a later date. Philips Semiconductors reserves the right to change the specification without notice, in order to improve the design and supply the best possible product.
III	Product data	Production	This data sheet contains data from the product specification. Philips Semiconductors reserves the right to make changes at any time in order to improve the design, manufacturing and supply. Relevant changes will be communicated via a Customer Product/Process Change Notification (CPCN).

[1] Please consult the most recently issued data sheet before initiating or completing a design.

[2] The product status of the device(s) described in this data sheet may have changed since this data sheet was published. The latest information is available on the Internet at URL <http://www.semiconductors.philips.com>.

[3] For data sheets describing multiple type numbers, the highest-level product status determines the data sheet status.

Definitions

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Date of release: 04-03

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